

## Design and Implementation of low power Fault Tolerant Hybrid Full Swing Full Adder for Neural Network Applications

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**Abstract:** Neural Networks (NN) are algorithms that can recognize relationships between data and can mimic the operation of the human brain. Some neurons are not fault free. Hence system that is fault tolerant is designed. Fault tolerance is one of the major factors that has to be considered while designing the VLSI circuit for critical applications. Implementation of a full adder using pass transistor logic has resulted in output degradation and CMOS logic has resulted in high power consumption. The fidelity of the sum output and carry output affects the fault tolerant capability of the full adder. Hence the aim of this work is to design and implement hybrid low power full adder with full swing at carry out. The proposed full swing full adder will be used to implement fault tolerant Self Repairing full adder. Fault tolerant Self Repairing full adder helps to detect the fault in the circuit and resolve the single and double faults. For the proposed system, even though the number of transistors is increased by 4 for the Hybrid one bit full adder and 4 for the Self Repairing full adder, the output swing is maintained as per the requirement but the power consumed is reduced by 15.4% for Hybrid full adder and 27.4% for self-repairing full adder.

**Keywords:** HybridFullAdder, faulttolerance, SelfRepairingFullAdder

### 1. Introduction

Fault is defined as the physical defect present in the circuit. This leads to improper functionality of the system. In order to avoid the damage, circuits are built that are fault tolerant in nature. This reduces the failures in the system but it is impossible to completely eradicate the fault from the systems. Neurons are not inherently fault free. In order to make a system fault free, neuron that constitutes of adder and multiplier should be made fault free [1].

Larger number of hardware faults results in transient faults. It is addressed using any of the redundancy schemes: timer redundancy, space redundancy, or information redundancy [2] along with polling logics, with power, area and delay overhead. Many methods are used for hardware fault detection and its recovery in digital circuits. To improve the yield of digital IC, the redundancy is used to achieve optimized area. Depending on the duration the fault manifests, it can be further categorized as permanent, transient and intermittent faults. Transient faults contribute majorly to the hardware faults which may be due to alpha particles, Gaussian noise in channel, corrosion, electromigration etc. This paper presents the implementation of 8-bit fault tolerant multiplier using the proposed full adder, mainly focusing on well-established circuit to improve by design and to reduce the area and power. The proposed full swing full adder will be used to implement fault tolerant Self Repairing full adder. Many approaches are available for Self Checking and Self Repairing full adder. There are advantages and disadvantages in all the approaches.

### 2. Literature review

#### 2.1 Redundancy

##### 2.1.1 Timer redundancy

Self Checking full adder requires redundancy. Here the redundancy check is performed by the original module along with the duplicate module [3]. Delay clock is being introduced in order to establish the difference in time interval for the duplicate module. The two outputs obtained at the different time intervals is compared to determine the fault in the systems. If the two outputs are same, then the system is fault free. If the two outputs are different, then there is presence of fault. Since similar operations are performed at different time interval, this helps to reduce the cost of the design and area.

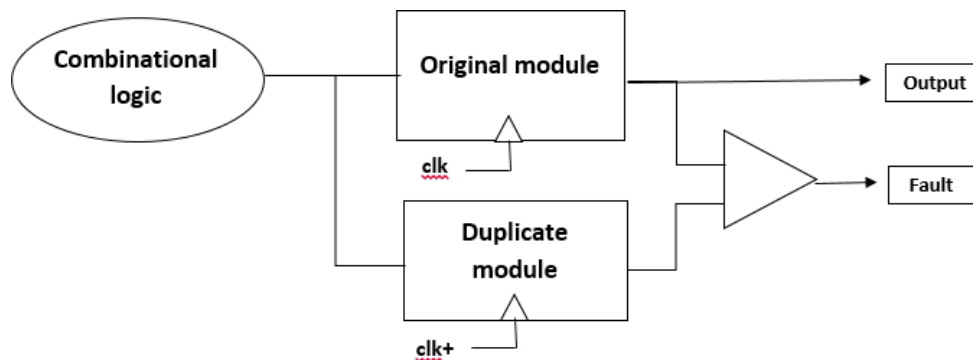


Figure1: Time Redundancy fault detection technique

### 2.1.2. Hardware Redundancy

In hardware redundancy, one or more duplicate circuit is used to produce outputs[3]. Here fault and fault free condition are determined by comparing the outputs obtained from the original and duplicate hardware module though they perform same operation.

### 2.1.3. Information redundancy

This method could be used for detecting real time faults. Error detection codes, predicted parity bits could be used for fault detection in combinational logic. The major drawback of area overhead can be solved by using multiple parity groups[3].

## 2.2 Low Power Full Adder Implementations

The full adder described in [4],[5] uses 16 transistors is a very prospective design for the application proposed in this paper as it has good output fidelity and has low power dissipation. It proposes GDI full swing method with optimized power dissipation and area.

The 18-T full adder described in [6] exhibits full swing at sum output but not at the carry out. 14 transistor implementation in [8] uses more than one style, and a hybrid pass transistor approach is adopted in [9]. Many low power adders that uses pass transistor logic, gate diffusion input and transmission gate [10] consumes larger power and results in output degradation. The 10-T full adder described in [11-12] exhibits degradation of output levels at both carry and sum. Even the Gate Diffusion –Input (GDI) based adder which has very low power dissipation also have very low output levels. These

Designs Lacks Drivin capabilities. Low static power dissipation can be achieved through branch based logic and pass-transistor proposed in [13] uses 23 transistors.

For any arithmetic, logical unit and neural networks adders and multipliers are the building Blocks. An Hybrid 20-T Full Adder that produces Full Swing at both the sum and Carry out is implemented in order to maintain the fidelity of the output. Several Implementations of one bit Full Adder are done over years [14-17].

## 3. Problem statement

In the existing architectures [4][6], it is found that there is no full swing at the carry output which results in improper output for the proposed design. In order to overcome this problem, a Hybrid Full Adder that produces full swing at the carry output with low power is implemented. The Self Repairing fault tolerant full adder is implemented using this hybrid full adder.

## 4. Proposed designs

### 4.1 Proposed 20-T Hybrid full adder

An adder is the basic module to construct the multiplier circuit. An adder performs the arithmetical and logical operations. A full adder is an adder that performs addition of 3 inputs which results in 2 outputs. It adds the first 2 inputs 'a' and 'b' along with the third input 'c' to obtain the 'sum' and 'cout' outputs. The XNOR gate

and the 2:1 multiplexer are the building blocks in this full adder design. The multiplexer is used in the design to generate the 'cout' output. 2:1 multiplexer is used for the following reasons:

1. It speeds up the propagation of carry.
2. It improves the output voltage swing.

The full swing for carry out had been attained with 20T hybrid full adder. Hybrid full adders are built using pass transistors and CMOS. The sum output is built using two 6 T XNOR gates and the carry output is built using multiplexer followed by buffer. The proposed full adder is used to design fault tolerant Self Repairing full adder that has less power consumption. The expressions for the carry and sum outputs of the full adder is shown in equation (1) and (2)

$$\text{sum} = a \oplus b \oplus \text{cin} \dots\dots\dots (1)$$

$$\text{cout} = ab + bc + \text{cin} \dots\dots\dots (2)$$

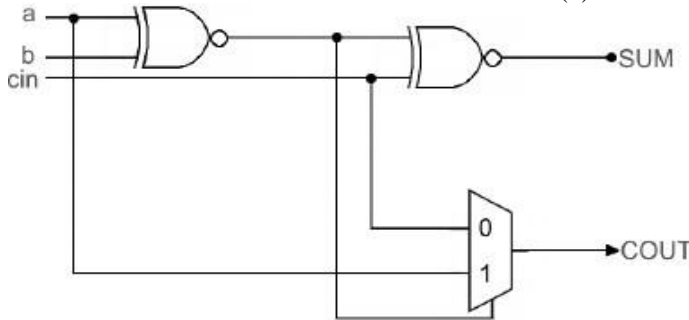


Figure 2: Proposed Hybrid 20-T Full Adder

#### 4.2 Self Checking full adder

The Self Checking adder along with two MUX and two inverters are used to implement the Self Repairing adder circuit. The proposed Self Checking full adder is used for detection of the faults with an exact location indication. The 'sum' and 'cout' are checked individually to detect the fault. The equivalent functional unit and xnor gates are used to identify the fault at the carry output. To detect the fault at the cout, Fc can be computed as

$$G1 = (\text{cout} \oplus \text{cin}) \dots\dots\dots (3)$$

$$F1 = (a \oplus b \oplus \text{cin}) \dots\dots\dots (4)$$

$$F_c = (G1 \oplus F1) \dots\dots\dots (5)$$

To detect the fault at the sum, Fs, can be computed as

$$G2 = (a \oplus b) \dots\dots\dots (6)$$

$$G3 = (\text{sum} \oplus \text{cin}) \dots\dots\dots (7)$$

$$F_s = (G2 \oplus G3) \dots\dots\dots (8)$$

For fault free condition,  $F_s = 1$ , and  $F_c = 0$ . The complementary values of these signals will indicate faulty condition. Fault location can be determined by the value of these two outputs. Both single and double faults can be detected.

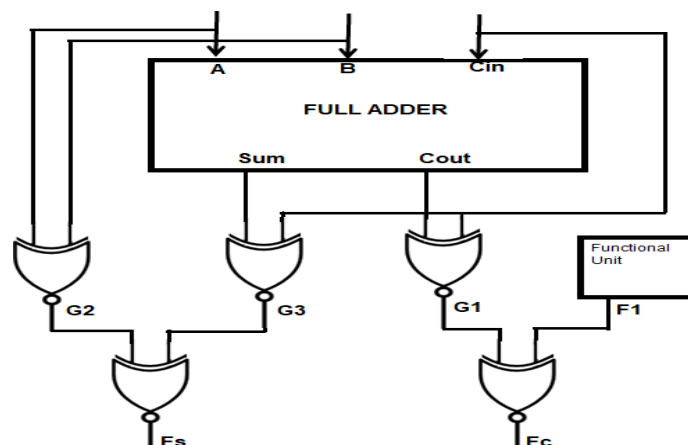


Figure 3: Block Diagram of Self Checking Full Adder

#### 4.3 Self Repairing full adder

The proposed Self Repairing full adder design is used for repair the faults that is detected in the Self Checkingfull adder. The fault tolerant Self Repairing full adder should have the ability to resolve fault permanently and make theadder faultfree.

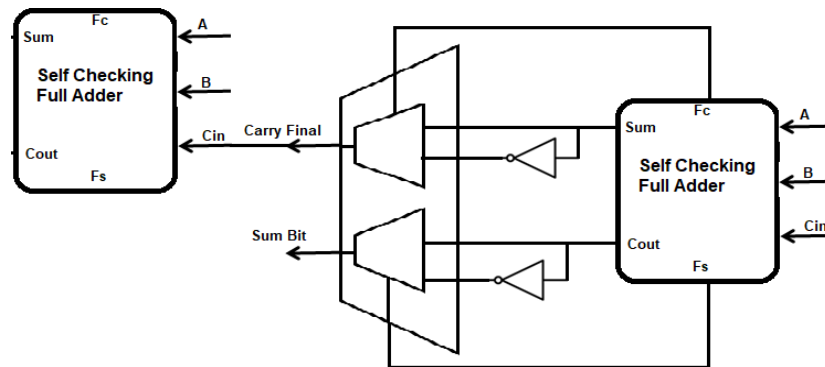


Figure4:BlockDiagramofSelfRepairing FullAdder.

## 5. Implementation

The design is implemented using using the Cadence Virtuoso Tool of gpdk45nm technology node.

### 5.1 Proposed 20T1-Bit Hybrid Full Adder

The Hybrid full adder is implemented using 20T as shown in below figure 5. There are two 6T XNOR gates and one 2x1 Mux followed by buffer. Transmission gate is used as 2:1 multiplexer. Multiplexer followed by buffer gives carry output with full swing.

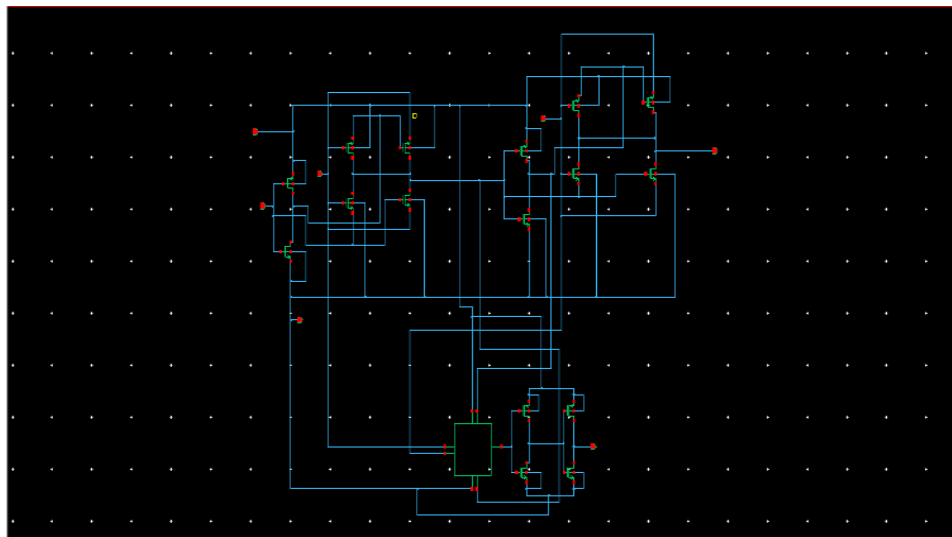


Figure5:SchematicofHybrid20TFullAdder

### 5.2 Self Checking Full Adder

It is built using one 20 transistor full adder, five XNOR gates (6 transistor) and a functional unit implemented using 14 transistors is shown in figure 6. The total number of transistors used in this implementation is 64.

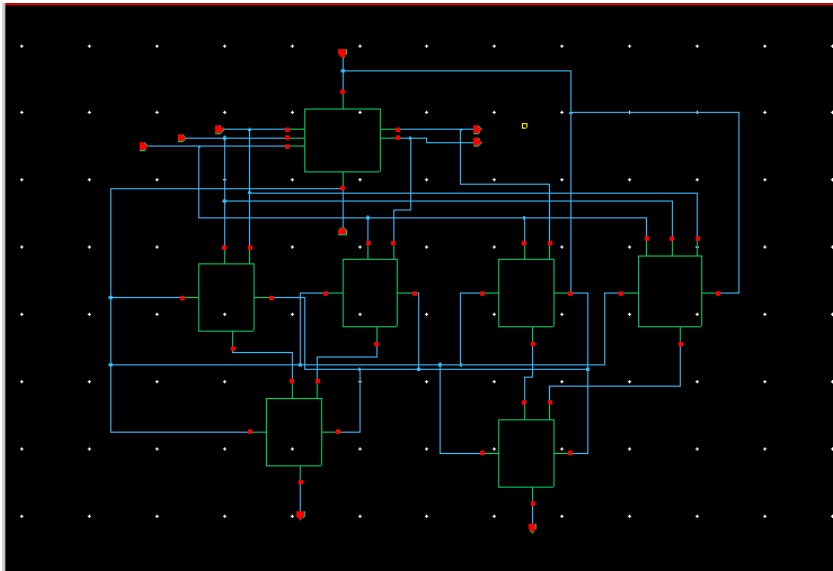


Figure6:SchematicofSelfCheckingFull Adder

### 5.3 SelfRepairingFullAdder

If fault occurs, it is corrected using multiplexer for both carry and sum outputs from the Self Checking process. The Self Checking adder along with two MUX and two inverters are used to implement the self-repairing adder circuit as shown in figure 7. The total transistor count for this design is 80.

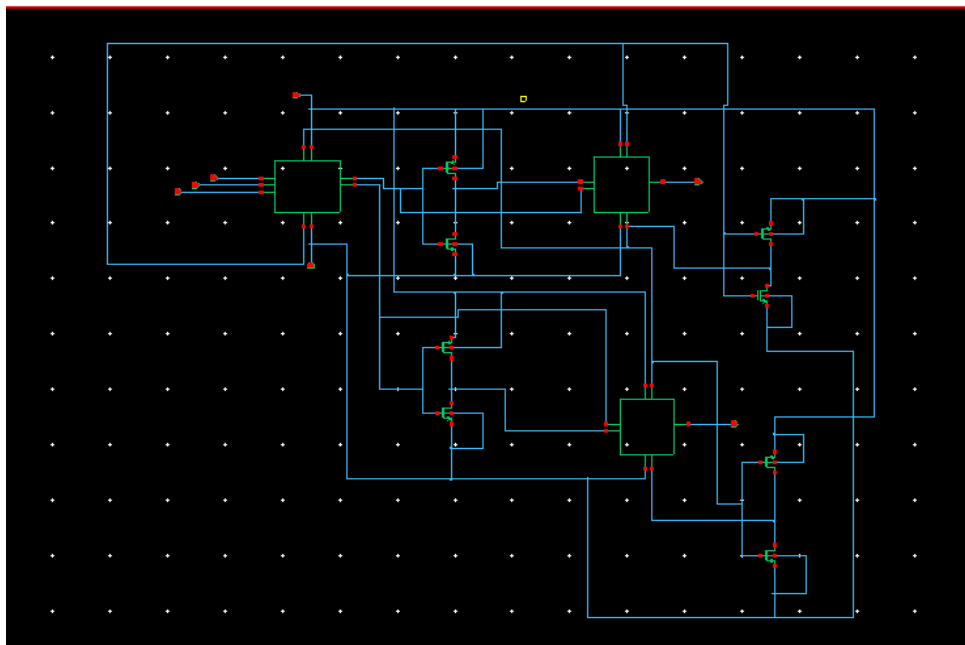


Figure7:SchematicofSelfRepairingFull Adder

## 6. Result and waveform

### 6.1 Proposed 20T1-Bit Hybrid Full Adder

The proposed design was designed in 45nm gpdk technology node and simulation is done using spectre cadence simulator. the size of pmos is twice that of nmos to get better delay and power performance ( $w_p/l = 240/45, w_n/l = 120/45$ ). The supply voltage is kept at 1V and frequency is maintained at 100MHz. figure 12 shows the simulation result of hybrid full adder which includes xnor gates and 2:1 mux of 20 transistors. The full swing operation is obtained for both sum and carry outputs at 1V each respectively.

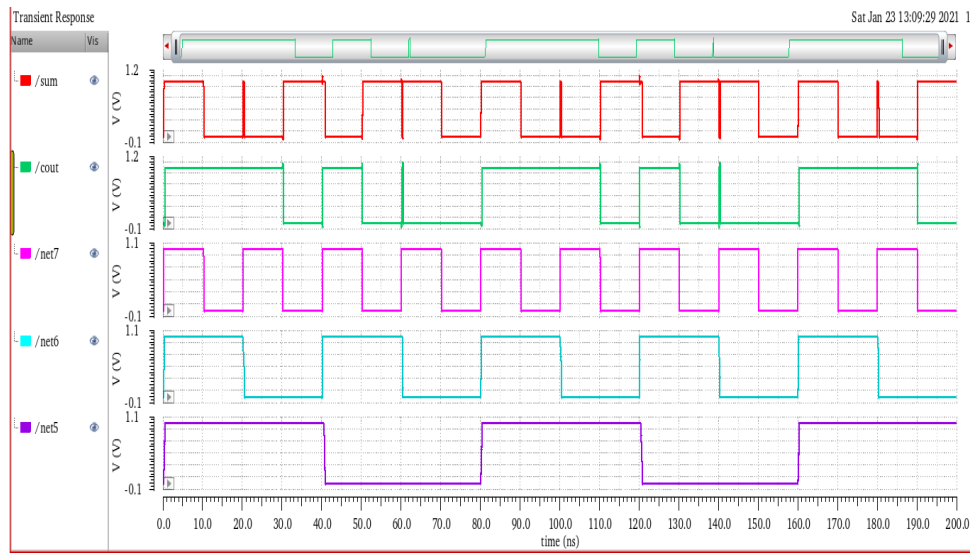


Figure8:SimulationResultofHybridFull Adder

### 6.2 SelfCheckingfulladder

Since there are no faults introduced during simulation of self-checking full adder, signal  $F_s=1$  and signal  $F_c=0$  as shown in figure 9.

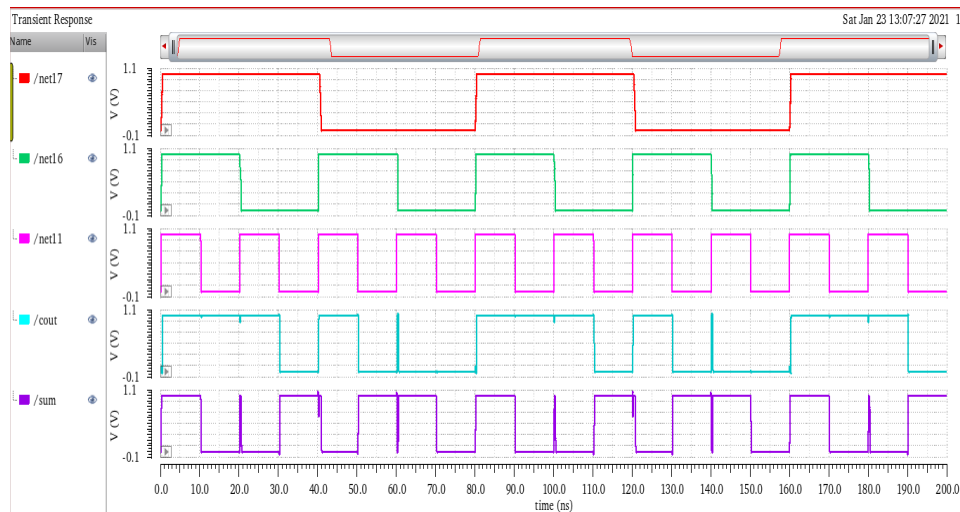


Figure9:SimulationResultofSelfChecking fulladder

### 6.3 SelfRepairingfulladder

The faults occurred is corrected using multiplexer for both carry and sum outputs from the SelfChecking process.

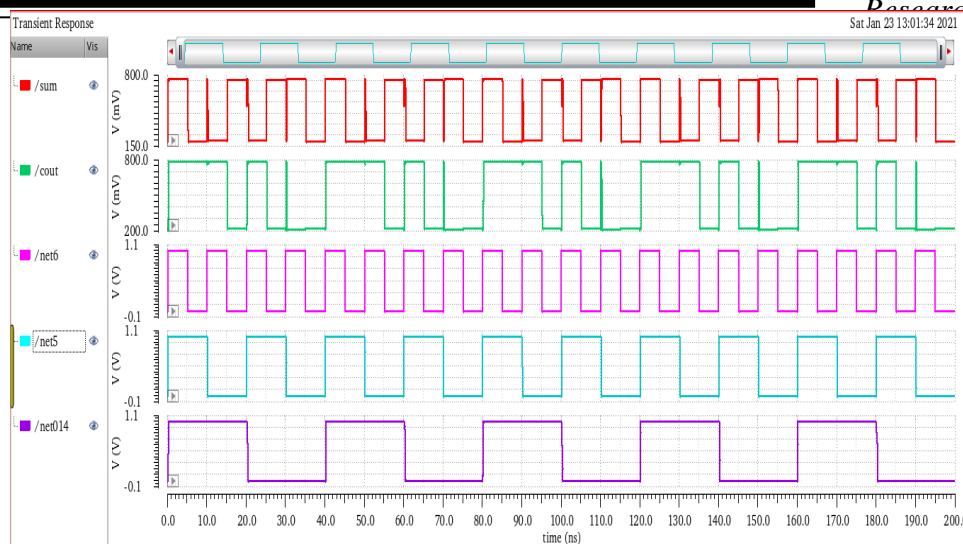


Figure10:SimulationResult of SelfRepairingfulladder

### 7. Comparisons

The various designs are compared in terms of the number of gates used and the total number of transistors used for implementing the designs as shown in Table 1. It is evident that the design proposed in this paper has a clear advantage on the total number of transistors used. Comparison of power is given in Table 2.

Table1:Comparison of number of transistors used

DesignName	List of gates	Numberofgates	Numberoftransistors used	Total
Self repairing	Fulladder	1	28	138
	XNOR	5	60	
	Functionalunit	1	28	
	NOT	2	4	
	MUX	2	20	
Selfrepairingfulladder [6]	Fulladder	1	16	76
	XNOR	5	30	
	Functional unit	1	14	
	NOT	4	8	
	MUX	2	8	
Selfrepairingfulladder [7]	Fulladder	1	114	138
	NOT	2	4	
	MUX	2	20	
Selfrepairingfulladder (GDI)[3]	Fulladder	1	18	96
	XNOR	5	40	
	Functionalunit	1	22	
	NOT	2	4	
	MUX	2	12	
Selfrepairingfulladder (Proposeddesign)	Fulladder	1	20	80
	XNOR	5	30	
	Functionalunit	1	14	
	NOT	4	8	
	MUX	2	8	

Table2:ComparisonofPower

DesignName	No:oftransistor	Powerdissipation	Technologynode
ExistingfulladderDesign [6]	16	59.01nW	45nm
ExistingFullAdder(GDI)Design[7]	18	693.5nW	65nm
ExistingSelfrepairingfulladderDesign[6]	76	97.803uW	45nm
ProposedHybridfulladderDesign	20	49.994nW	45nm
ProposedSelfRepairAdderDesign	80	70.683uW	45nm

## 8. Conclusion

Even if Neural Network is considered as fault tolerant, they are not inherently fault tolerant. Implementation of fault free Self Repairing full adder can result in a neural network architecture that is fault free. The proposed full adder design with Self Repairing capability can identify and repair single fault and double fault at the same time. The aim of fault-tolerant circuit is to reduce the probability of failures. The desired output waveforms are obtained, hence the design can be further extended for neural network applications. The area and power consumption is reduced using the above design methodology. The transient faults occurring in critical applications which are crucial are solved by this proposed method. The total power consumed by the Hybrid Full Adder is 49.994 nW and Self Repairing Full Adder is 70.683 uW. The above comparison shows that the power consumption of proposed method is much more reduced compared to the existing method. A Hybrid 1-bit Full adder is designed with 15.4% decrease in the power consumption and Self Repairing full adder by 27.4% compared to existing Full Adder [4] even though the number of transistor is increased by 4. Though the number of transistors used in proposed system is more than the existing design [4], the power consumption is reduced comparatively. The degraded carry output [4] at the full adder end is propagated to the carry out of Self Checking full adder which results in high degraded output. This disadvantage of degraded output in paper [4] has been mitigated. The carry out and sum output of proposed full adders are both at 1V.

## 9. Future scope

Multipliers can be implemented using Proposed Self-Repairing adders. This can reduce the hardware redundancy that is used in rail checking circuits which can be used in conventional fault tolerant mechanism. Implementation of 8-bit Multipliers using adders results in power reduction that can be used in low power neural network automotive applications.

## 10. Acknowledgment

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